## Notice of References Cited Application/Control No. 10/602,678 Applicant(s)/Patent Under Reexamination SEKI ET AL. Examiner Dustin Nguyen Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0062392	05-2002	Nishikawa et al.	709/246
*	В	US-4,825,209	04-1989	Sasaki et al.	340/825.72
*	С	US-7,039,858	05-2006	Humpleman et al.	715/501.1
*	D	US-5,959,536	09-1999	Chambers et al.	710/104
*	E	US-2002/0163534	11-2002	Choi et al.	345/734
*	F	US-2002/0169845	11-2002	Szucs et al.	709/208
*	G	US-2002/0021465	02-2002	Moore et al.	359/125
*	Η	US-6,789,208	09-2004	Noda et al.	713/323
*	1	US-2002/0021372	02-2002	Konda et al.	348/730
	j	US-			
	·ĸ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					·
	Q	,				
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.